

Reliability Results for Product Type IP4264CZ8-20-TTL

Time period: Q1/2018 to Q4/2018

Test Results

Test	Conditions	Duration	Quantity	Rejects
TEST				
# 1	Pre- and Post-Stress Electrical Test $T_{amb} = 25\text{ °C}$	N/A	all parts	see below
# 2	PC Preconditioning JESD22-A113 Bake $T_{amb} = 125\text{ °C}$ Soak $T_{amb} = 85\text{ °C}$, RH = 85% Reflow soldering	24 hours 168 hours 3 cycles	8435	0
# 5	HTRB High Temperature Reverse Bias MIL-STD-750-1 M1038 Method A $T_j = T_{jmax}$, $V_r = 100\%$ of max. datasheet reverse voltage	1000 hours	8240	0
# 7	TC Temperature Cycling JESD22-A104 -55 °C to T_{jmax} , not to exceed 150 °C	1000 cycles	3150	0
# 8	AC Autoclave JESD22-A102 $T_{amb} = 121\text{ °C}$, RH = 100 % Pressure = 205 kPa (29.7 psia)	96 hours	2000	0
# 9	H3TRB High Humidity High Temperature Reverse Bias JESD22-A101 $T_{amb} = 85\text{ °C}$, RH = 85%, $V_R > 80\%$ of rated reverse voltage	1000 hours	3285	0
# 10	IOL Intermittent Operating Life MIL-STD-750 Method 1037 $t_{on} = t_{off}$, devices powered to insure $\Delta T_j = 100\text{ °C}$ for 15000 cycles	1000 hours	n.a.	n.a.
# 20	RSH Resistance to Solder Heat JESD22-A111 $260\text{ °C} \pm 5\text{ °C}$	10 s	360	0
# 21	SD Solderability J-STD-002 Test method B and D		180	0

Calculation of FIT and MTBF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test # 5)

Confidence level 60%, derated to 55 °C , activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate	MTBF
Nexperia DHAM	Protection	8240	0	0.52 FIT	221351 years